



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE

SHEET 15 OF 15
(REV. 7-80)RECEIVED
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F-1600/2900**LIST OF REFERENCES CITED BY APPLICANT**

(Use Several Sheets if Necessary)

DOCKET NO.: 5408/11295-US2 SERIAL NO: 10/087,207
APPLICANT: Patrick J. Lutz FILING DATE: February 28, 2002
CONFIRMATION NO: 7037

U.S. PATENT DOCUMENTS

*EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
Awf Dwy	1. 3,097,131	7/9/63	Ueno et al.	167	31	4/1/60
	2. 4,844,891	7/4/89	Rosen et al.	424	76	2/3/88
	3. 5,073,570	12/17/91	Tseng	514	533	2/16/89
	4. 5,670,160	9/23/97	Eggensperger et al.	424	405	1/30/96
	5. 5,885,593	3/23/99	Epstein	424	401	7/17/96
	6. 4,585,795	4/29/1986	Linderborg	514	558	4/24/85

FOREIGN PATENT DOCUMENTS

*EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
Awf Dwy	7. 99/07331	2/18/99	WO	A61K	7/00	X
	8. 99/37172	7/29/99	WO	A23L	3/34	X
	9. 94/27436	12/8/94	WO	A01N	31/00	X
	10. 2045337	4/1/71	DE	A61 1	13/00	abstract
	11. 3308303	9/29/83	DE	A01N	37/00	abstract
	12. 4026756	2/27/92	DE	A01N	47/44	abstract
	13. 0265202	10/19/87	EP	A01N	59/26	X
	14. 0339121	4/29/88	EP	A61K	7/48	X
	15. 0974359	7/16/99	EP	A61K	38/24	X
	16. 999145	1/18/99	JP	A61K	031/60	abstract
	17. 95141346	5/17/95	JP	A61K	007/075	abstract
	18. 99326614	5/22/01	JP	C11D	010/02	abstract
	19. 94259415	9/28/94	JP	A01N	037/40	abstract
	20. 5229904	9/7/93	JP	A01N	33/12	abstract
	21. 4942901	9/6/72	JP			X
	22. 5350245	5/8/78	JP	C08K	5/09	abstract
	23. 57058625	04/08/82	JP	A61K	31/19	abstract
	24. 56123906	9/29/81	JP	A01N	33/12	abstract
	25. 57058624	08/04/82	JP	A61K	31/19	abstract



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APPLICANT: Patrick J. Lutz

SERIAL NO: 10/087207
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26. 1301316	12/29/72	GB	A61L	13/00	X
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*EXAMINER
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28. International Search Report; PCT/US02/06305; Feb. 28, 2002.

EXAMINER:

Alton Pryor

DATE CONSIDERED:

3/1/03

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Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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<i>Amf</i>	1. 6-313269	11/8/94	JP	D06M	13/425	X

OTHER REFERENCES**(INCLUDING AUTHOR, TITLE DATE, PERTINENT PAGES, ETC.)**

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EXAMINER:

Altan Pryor

DATE CONSIDERED:

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